Application/Control No. Applicant(s)/Patent Under Reexamination 10/636,022 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2821 Hoang V Nguyen **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 343/700.0MS 05-2004 Kuo Dai et al. Α US-2004/0090374 A1 08-2004 343/700MS US-6,781,546 B2 Wang et al. В 11-2004 Tai et al. 343/700MS С US-6,812,892 B2 D US-US-Ε US-F G US-US-Н US-١ J US-K US-US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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